

Lecture 14: Wires

Outline

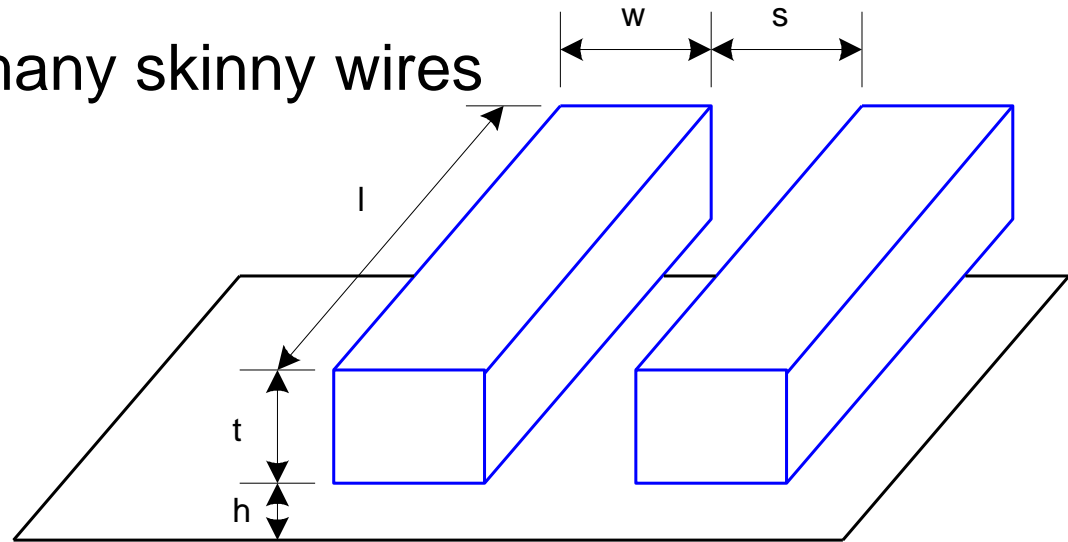
- ☐ Introduction
- ☐ Interconnect Modeling
 - Wire Resistance
 - Wire Capacitance
- ☐ Wire RC Delay
- ☐ Crosstalk
- ☐ Wire Engineering
- ☐ Repeaters

Introduction

- ❑ Chips are mostly made of wires called *interconnect*
 - In stick diagram, wires set size
 - Transistors are little things under the wires
 - Many layers of wires
- ❑ Wires are as important as transistors
 - Speed
 - Power
 - Noise
- ❑ Alternating layers run orthogonally

Wire Geometry

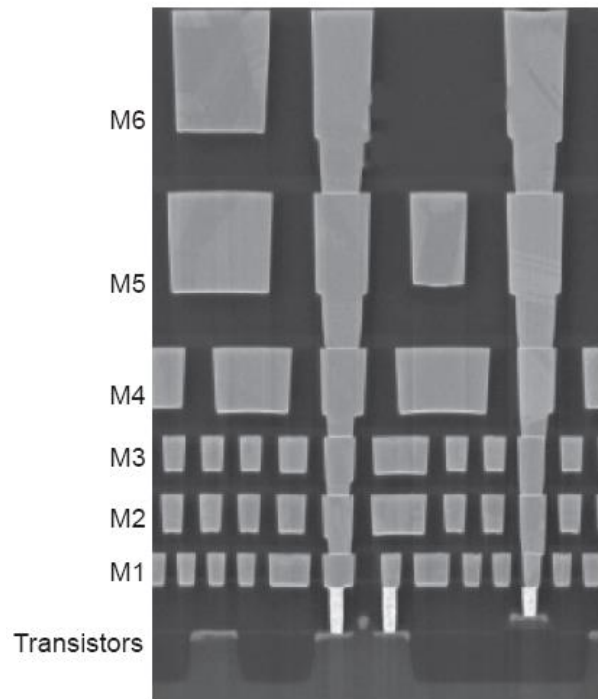
- ❑ Pitch = $w + s$
- ❑ Aspect ratio: $AR = t/w$
 - Old processes had $AR \ll 1$
 - Modern processes have $AR \approx 2$
 - Pack in many skinny wires



Layer Stack

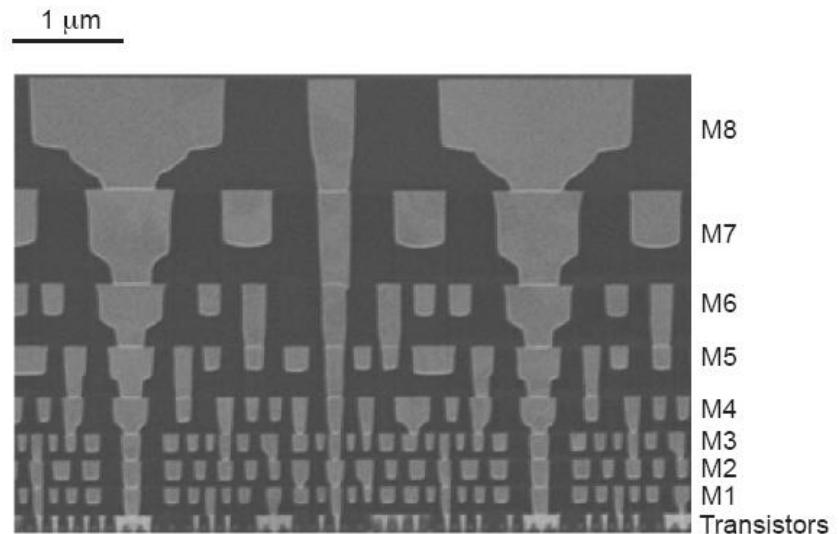
- ❑ AMI 0.6 μm process has 3 metal layers
 - M1 for within-cell routing
 - M2 for vertical routing between cells
 - M3 for horizontal routing between cells
- ❑ Modern processes use 6-10+ metal layers
 - M1: thin, narrow ($< 3\lambda$)
 - High density cells
 - Mid layers
 - Thicker and wider, (density vs. speed)
 - Top layers: thickest
 - For V_{DD} , GND, clk

Example



Intel 90 nm Stack

[Thompson02]

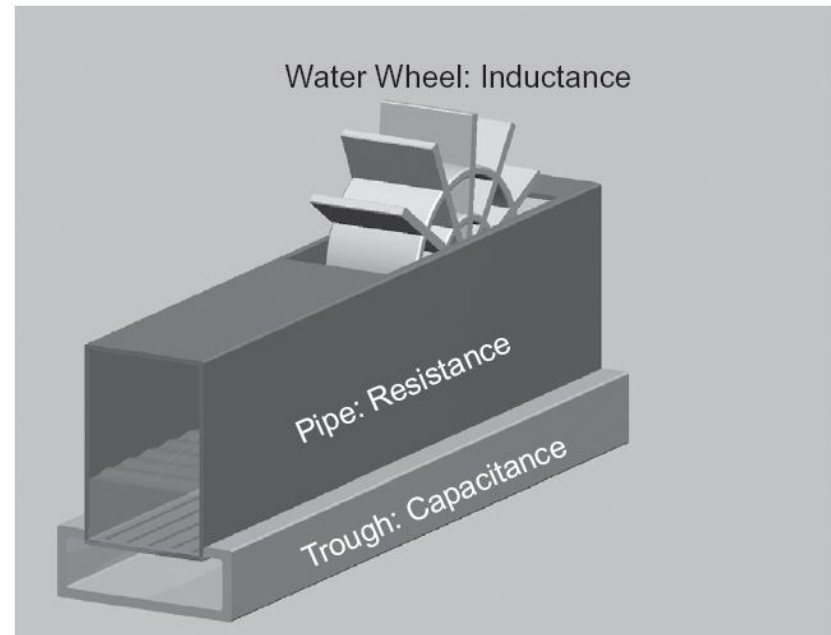


Intel 45 nm Stack

[Moon08]

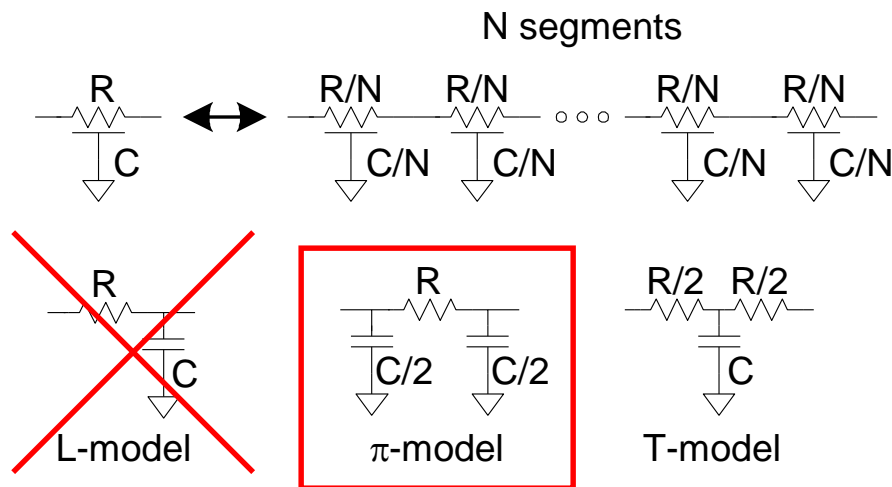
Interconnect Modeling

- ❑ Current in a wire is analogous to current in a pipe
 - Resistance: narrow size impedes flow
 - Capacitance: trough under the leaky pipe must fill first
 - Inductance: paddle wheel inertia opposes changes in flow rate
 - Negligible for most wires



Lumped Element Models

- ❑ Wires are a distributed system
 - Approximate with lumped element models



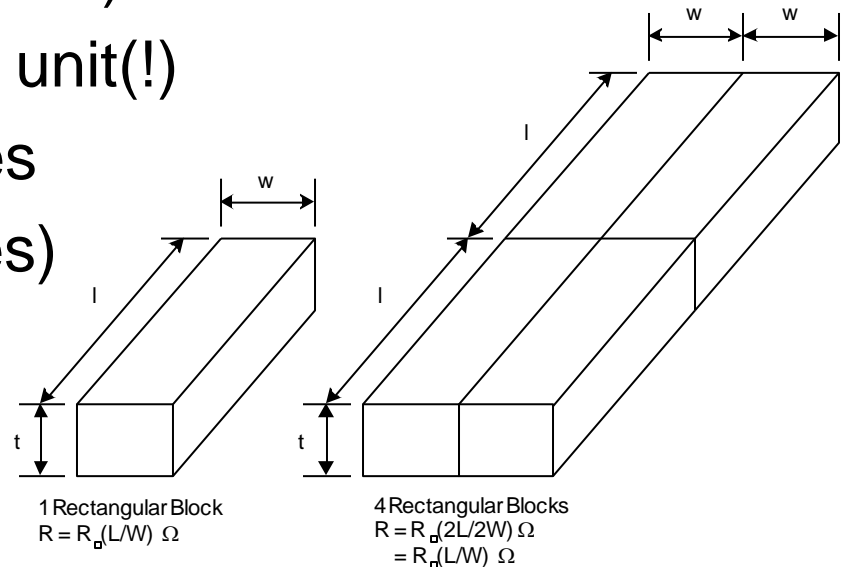
- ❑ 3-segment π -model is accurate to 3% in simulation
- ❑ L-model needs 100 segments for same accuracy!
- ❑ Use single segment π -model for Elmore delay

Wire Resistance

□ $\rho = \text{resistivity } (\Omega \cdot \text{m})$

$R =$

- $R_{\square} = \text{sheet resistance } (\Omega/\square)$
 - \square is a dimensionless unit(!)
- Count number of squares
 - $R = R_{\square} * (\# \text{ of squares})$



Choice of Metals

- ❑ Until 180 nm generation, most wires were aluminum
- ❑ Contemporary processes normally use copper
 - Cu atoms diffuse into silicon and damage FETs
 - Must be surrounded by a diffusion barrier

Metal	Bulk resistivity ($\mu\Omega \cdot \text{cm}$)
Silver (Ag)	1.6
Copper (Cu)	1.7
Gold (Au)	2.2
Aluminum (Al)	2.8
Tungsten (W)	5.3
Titanium (Ti)	43.0

Contacts Resistance

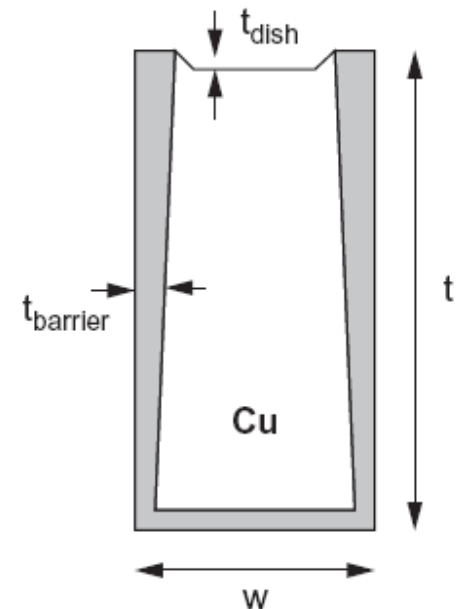
- ❑ Contacts and vias also have 2-20 Ω
- ❑ Use many contacts for lower R
 - Many small contacts for current crowding around periphery



Copper Issues

- ❑ Copper wires diffusion barrier has high resistance
- ❑ Copper is also prone to *dishing* during polishing
- ❑ Effective resistance is higher

$$R = \frac{\rho}{(t - t_{\text{dish}} - t_{\text{barrier}})} \frac{l}{(w - 2t_{\text{barrier}})}$$



Example

- ❑ Compute the sheet resistance of a $0.22\text{ }\mu\text{m}$ thick Cu wire in a 65 nm process. The resistivity of thin film Cu is $2.2 \times 10^{-8}\text{ }\Omega\cdot\text{m}$. Ignore dishing.

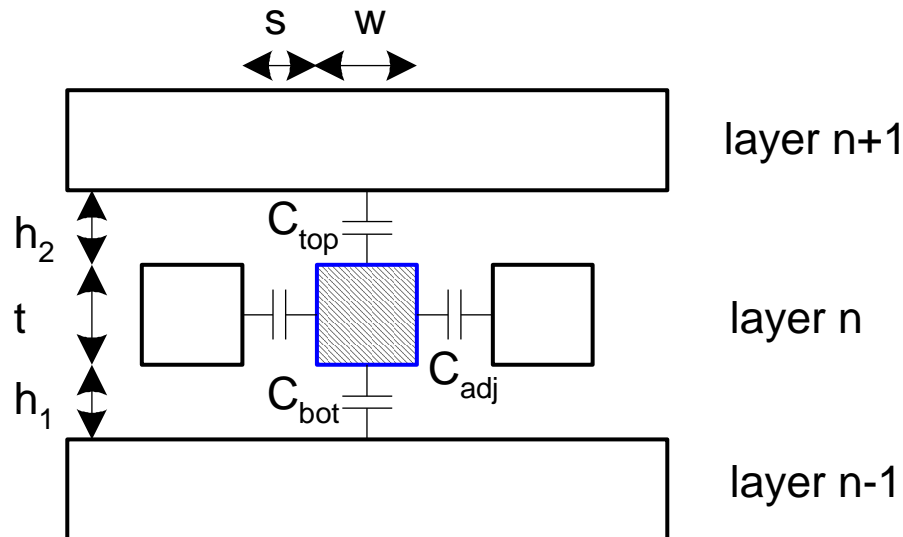
$$R_{\square} =$$

- ❑ Find the total resistance if the wire is $0.125\text{ }\mu\text{m}$ wide and 1 mm long. Ignore the barrier layer.

$$R =$$

Wire Capacitance

- ❑ Wire has capacitance per unit length
 - To neighbors
 - To layers above and below
- ❑ $C_{\text{total}} = C_{\text{top}} + C_{\text{bot}} + 2C_{\text{adj}}$



Capacitance Trends

- ❑ Parallel plate equation: $C = \epsilon_{ox} A/d$
 - Wires are not parallel plates, but obey trends
 - Increasing area (W, t) increases capacitance
 - Increasing distance (s, h) decreases capacitance
- ❑ Dielectric constant
 - $\epsilon_{ox} = k\epsilon_0$
 - $\epsilon_0 = 8.85 \times 10^{-14} \text{ F/cm}$
 - $k = 3.9$ for SiO_2
- ❑ Processes are starting to use low-k dielectrics
 - $k \approx 3$ (or less) as dielectrics use air pockets

Capacitance Formula

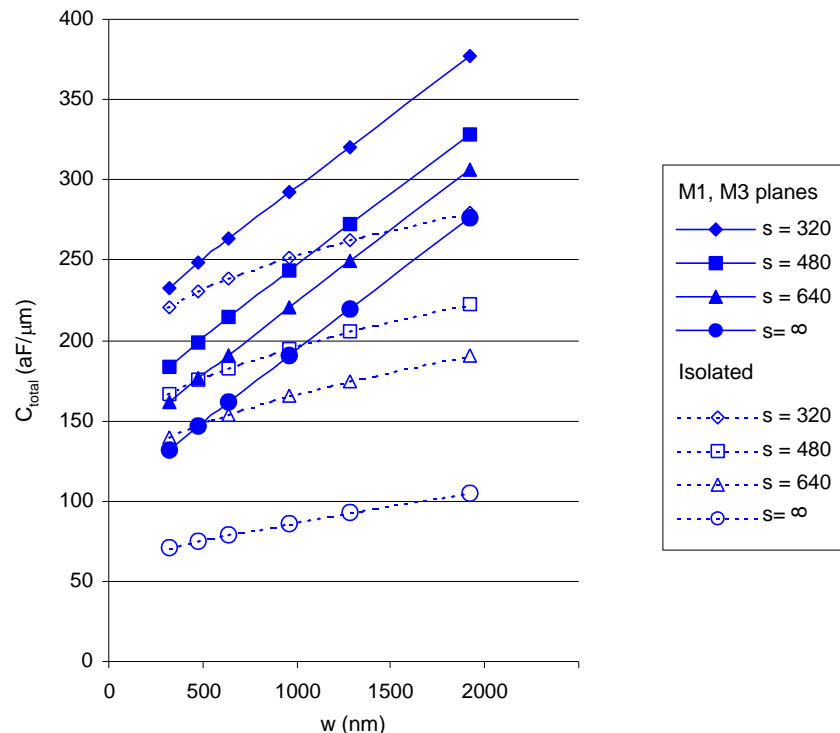
- ❑ Capacitance of a line without neighbors can be approximated as

$$C_{tot} = \epsilon_{ox} l \left[\frac{w}{h} + 0.77 + 1.06 \left(\frac{w}{h} \right)^{0.25} + 1.06 \left(\frac{t}{h} \right)^{0.5} \right]$$

- ❑ This empirical formula is accurate to 6% for $AR < 3.3$

M2 Capacitance Data

- Typical dense wires have ~ 0.2 fF/ μm
 - Compare to 1-2 fF/ μm for gate capacitance



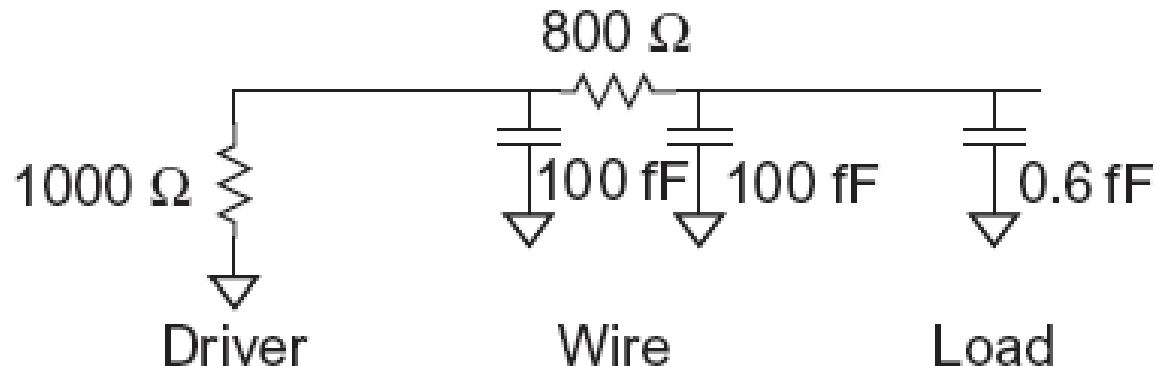
Diffusion & Polysilicon

- ❑ Diffusion capacitance is very high ($1\text{-}2\text{ fF}/\mu\text{m}$)
 - Comparable to gate capacitance
 - Diffusion also has high resistance
 - Avoid using diffusion *runners* for wires!
- ❑ Polysilicon has lower C but high R
 - Use for transistor gates
 - Occasionally for very short wires between gates

Wire RC Delay

- Estimate the delay of a 10x inverter driving a 2x inverter at the end of the 1 mm wire. Assume wire capacitance is $0.2 \text{ fF}/\mu\text{m}$ and that a unit-sized inverter has $R = 10 \text{ K}\Omega$ and $C = 0.1 \text{ fF}$.

– $t_{pd} =$



Wire Energy

- ❑ Estimate the energy per unit length to send a bit of information (one rising and one falling transition) in a CMOS process.

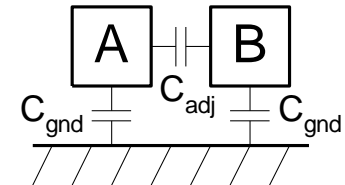
❑ $E =$

Crosstalk

- ❑ A capacitor does not like to change its voltage instantaneously.
- ❑ A wire has high capacitance to its neighbor.
 - When the neighbor switches from 1- \rightarrow 0 or 0- \rightarrow 1, the wire tends to switch too.
 - Called capacitive *coupling* or *crosstalk*.
- ❑ Crosstalk effects
 - Noise on nonswitching wires
 - Increased delay on switching wires

Crosstalk Delay

- ❑ Assume layers above and below on average are quiet
 - Second terminal of capacitor can be ignored
 - Model as $C_{\text{gnd}} = C_{\text{top}} + C_{\text{bot}}$
- ❑ Effective C_{adj} depends on behavior of neighbors
 - *Miller effect*

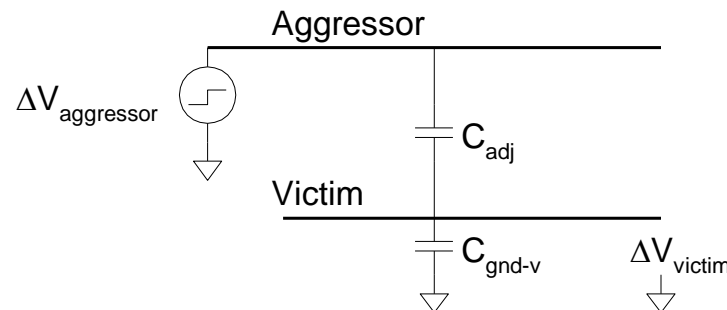


B	ΔV	$C_{\text{eff(A)}}$	MCF
Constant	---	---	---
Switching with A	---	---	---
Switching opposite A	---	---	---

Crosstalk Noise

- ❑ Crosstalk causes noise on nonswitching wires
- ❑ If victim is floating:
 - model as capacitive voltage divider

$$\Delta V_{victim} = \frac{C_{adj}}{C_{gnd-v} + C_{adj}} \Delta V_{aggressor}$$

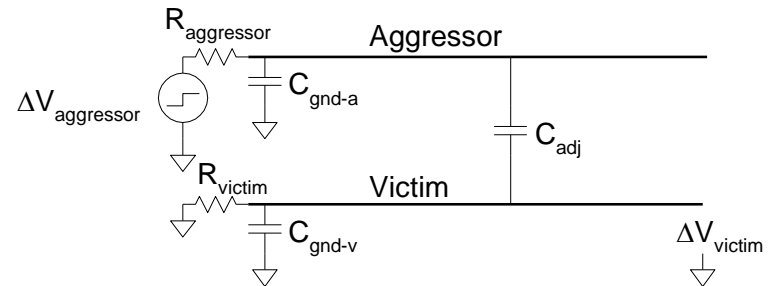


Driven Victims

- Usually victim is driven by a gate that fights noise
 - Noise depends on relative resistances
 - Victim driver is in linear region, agg. in saturation
 - If sizes are same, $R_{\text{aggressor}} = 2-4 \times R_{\text{victim}}$

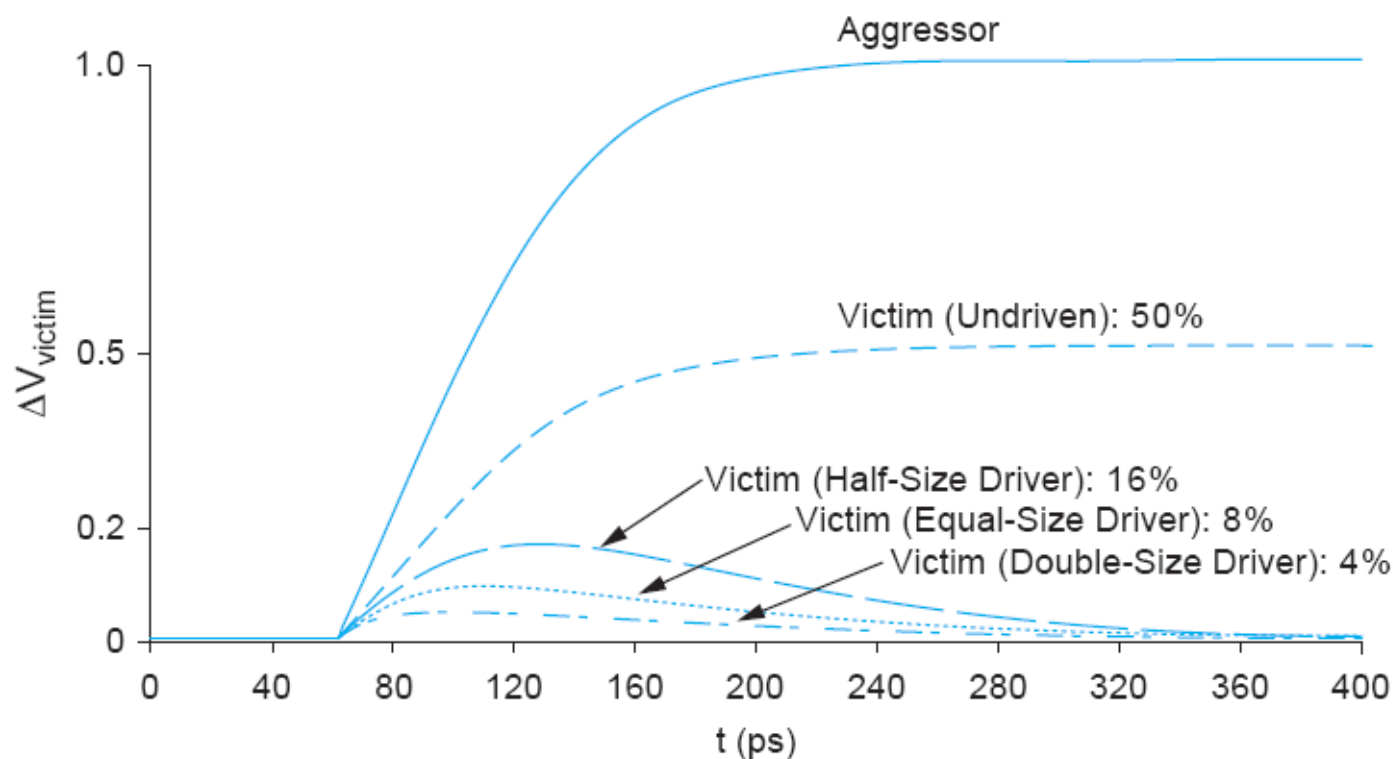
$$\Delta V_{\text{victim}} = \frac{C_{\text{adj}}}{C_{\text{gnd-v}} + C_{\text{adj}}} \frac{1}{1+k} \Delta V_{\text{aggressor}}$$

$$k = \frac{\tau_{\text{aggressor}}}{\tau_{\text{victim}}} = \frac{R_{\text{aggressor}} (C_{\text{gnd-a}} + C_{\text{adj}})}{R_{\text{victim}} (C_{\text{gnd-v}} + C_{\text{adj}})}$$



Coupling Waveforms

- Simulated coupling for $C_{\text{adj}} = C_{\text{victim}}$



Noise Implications

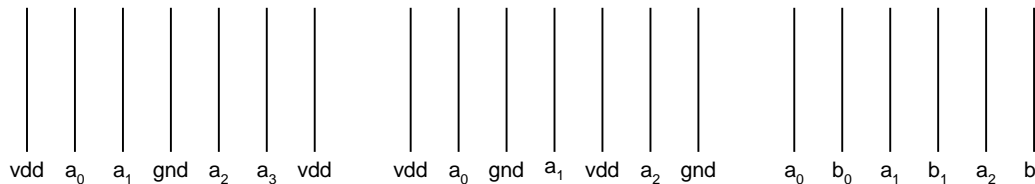
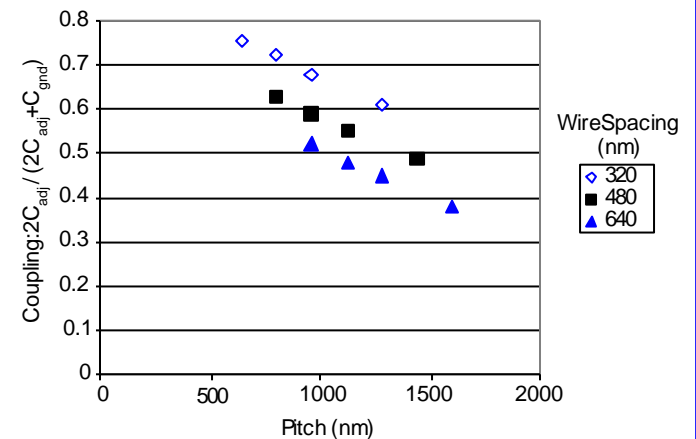
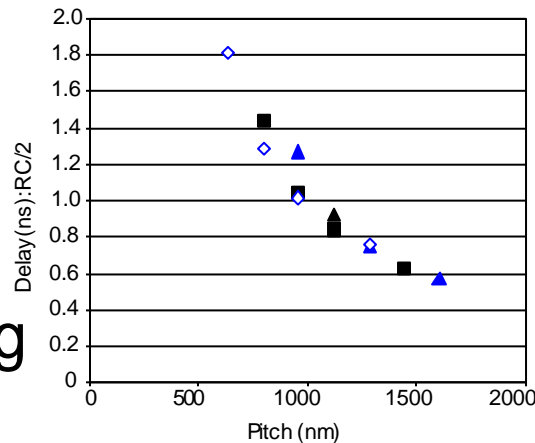
- ❑ *So what* if we have noise?
- ❑ If the noise is less than the noise margin, nothing happens
- ❑ Static CMOS logic will eventually settle to correct output even if disturbed by large noise spikes
 - But glitches cause extra delay
 - Also cause extra power from false transitions
- ❑ Dynamic logic never recovers from glitches
- ❑ Memories and other sensitive circuits also can produce the wrong answer

Wire Engineering

❑ Goal: achieve delay, area, power goals with acceptable noise

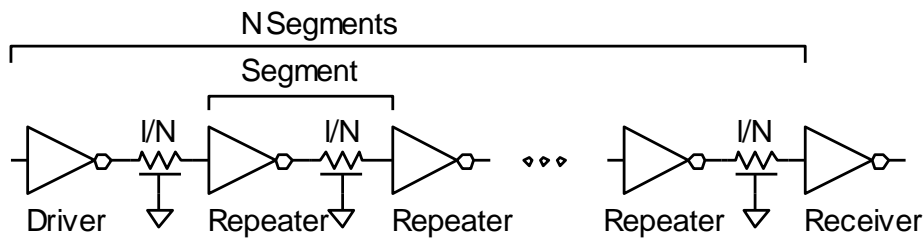
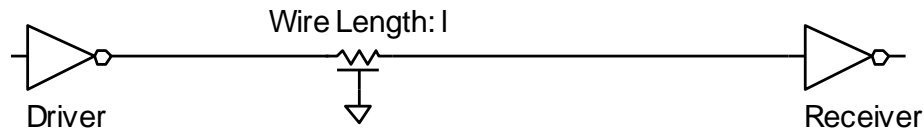
❑ Degrees of freedom:

- Width
- Spacing
- Layer
- Shielding



Repeaters

- ❑ R and C are proportional to
- ❑ RC delay is proportional to
 - Unacceptably great for long wires
- ❑ Break long wires into N shorter segments
 - Drive each one with an inverter or buffer



Repeater Design

- ❑ How many repeaters should we use?
- ❑ How large should each one be?
- ❑ Equivalent Circuit
 - Wire length l/N
 - Wire Capacitance $C_w * l/N$, Resistance $R_w * l/N$
 - Inverter width W (nMOS = W , pMOS = $2W$)
 - Gate Capacitance $C' * W$, Resistance R/W

Repeater Results

- Write equation for Elmore Delay
 - Differentiate with respect to W and N
 - Set equal to 0, solve

$$\frac{l}{N} = \sqrt{\frac{2RC'}{R_w C_w}}$$

$$\frac{t_{pd}}{l} = \left(2 + \sqrt{2}\right) \sqrt{RC'R_w C_w} \quad \begin{array}{l} \sim 40 \text{ ps/mm} \\ \text{in 65 nm process} \end{array}$$

$$W = \sqrt{\frac{RC_w}{R_w C'}}$$

Repeater Energy

- ❑ Energy / length $\approx 1.87C_w V_{DD}^2$
 - 87% premium over unpeated wires
 - The extra power is consumed in the large repeaters
- ❑ If the repeaters are downsized for minimum EDP:
 - Energy premium is only 30%
 - Delay increases by 14% from min delay